Algorithms and Lower Bounds: Some Basic Connections Lecture 3: Circuit Complexity and Connections - PART II

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SAT and Lower Bounds [W'10,'11,'13]

A slightly faster algorithm for C-SAT \Rightarrow Lower bounds against C circuits



Faster Algorithms ⇒ Lower Bounds

Faster "Algorithms for Circuits"

An algorithm for:

- Circuit SAT in O(2ⁿ/n¹⁰) (n inputs and n^k gates)
- Formula SAT in O(2ⁿ/n¹⁰)
- ACC SAT in O(2ⁿ/n¹⁰)

• Given a circuit C that's either UNSAT, or has $\geq 2^{n-1}$ satisfying assignments, determine which, in O(2ⁿ/n¹⁰) time (A Promise-BPP problem) No "Circuits for Algorithms"

Would imply:

- NEXP ⊄ P/poly
- NEXP ⊄ (non-uniform) NC¹
- NEXP $\not\subset$ ACC

NEXP $\not\subset$ **P/poly**

Converse: Can interesting circuit *lower bounds* tell us something about circuit-analysis algorithms?

Many well-known connections between *circuit lower bounds* and *derandomization* e.g. EXP ⊄ P/poly ⇒ BPP is in SUBEXP

For *restricted* circuits, sometimes the techniques used to prove *circuit lower bounds* can be used to derive faster *SAT algorithms*

Example: Boolean formulas over AND, OR, NOT, fan-in 2 [Subbotovskaya '61] MOD2 on n bits cannot be computed with n^{1.4999} size Boolean formulas with AND, OR, NOT gates

[Santhanam'11] Satisfiability of O(n)-size Boolean formulas with AND and OR gates can be solved in o(2ⁿ) time

Converse: Can interesting circuit *lower bounds* tell us something about circuit-analysis algorithms?

For *restricted* circuits, sometimes the techniques used to prove *circuit lower bounds* can be used to derive faster *SAT algorithms* [CKKSZ14] "Mining circuit lower bound proofs for meta-algs"

Can "mine circuit lower bound proofs" for other algorithms! [W'14] [AWY'15], [AW'15] applied the polynomial method of R-S to yield faster algorithms for many problems:

- Solve all-pairs shortest paths in $\frac{n^3}{2\sqrt{\log n}}$ time
- Find a disjoint pair of sets among a set system
- Compute partial match queries in batch
- Evaluate a CNF formula on many chosen assignments
- Find a longest common substring with don't cares
- Solve 0-1 Integer LP faster than 2ⁿ time
- Find a closest pair of points in the Hamming metric

Are interesting circuit *lower bounds equivalent* to interesting circuit-analysis algorithms?

[Impagliazzo-Kabanets-Wigderson'02] There are "non-trivial" CAPP algorithms IF AND ONLY IF NEXP is not in P/poly

What does non-trivial mean?

We call a nondeterministic algorithm A "non-trivial for CAPP" if:

- For every ε , A(C) runs in $2^{n^{\varepsilon}}$ time on circuits C of size n and uses n^{ε} bits of advice
- For infinitely many n, there's ≥ 1 accepting computation path on all C of size n, and every accepting path outputs a value vwithin 1/10 of the acceptance probability of C

Are interesting circuit *lower bounds equivalent* to interesting circuit-analysis algorithms?

[W '13] There are "non-trivial" algorithms for MCSP IF AND ONLY IF NEXP is not in P/poly

What does non-trivial mean?

We call an algorithm A "non-trivial for MCSP" if for all k,

- A(f) runs in poly(2ⁿ) time on any Boolean function f of 2ⁿ bits and uses n bits of advice
- For infinitely many n, there is a Boolean function f of 2ⁿ bits such that A(f) outputs 1, and for all f computable with an n^k size circuit, A(f) outputs 0

Contrast with Natural Proofs!

[CW'15] New equivalence between algs + complexity Let $f: \{0,1\}^* \rightarrow \{0,1\}$ be a desired function. Let C be some "simple" class of Boolean circuits. Define C-Test For f to be the problem: Input: A circuit C from C; n(C) = number of inputs to C Decide: Does C compute f restricted to $\{0,1\}^{n(C)}$?

This is a very well-motivated problem from practice! We have a specification *f* and want to verify if C meets it

Define C-Test For f to be the problem:
 Input: A circuit C from C; let n(C) = number of inputs to C
 Decide: Does C compute f restricted to {0,1}^{n(C)}?

We gauge the complexity of *C*-Test For *f* by *measuring the number of inputs needed to test if a given circuit computes f:*

The *data complexity of the* C-Test For f is a function $T : \mathbb{N} \to \mathbb{N}$

- **T**(*s*) := the minimum number of labeled examples (*x*, *f*(*x*)) necessary and sufficient to determine for all $C \in C$ of size *s* whether C computes *f* on all n(C)-bit inputs
- This is also well-motivated! Small data complexity means we can rapidly determine if C computes *f*

Theorem: For every function $f: \{0,1\}^* \rightarrow \{0,1\}$, Lower Bounds on the data complexity of *C*-Test For f*are equivalent to* Upper Bounds on the *C* circuit complexity of *f*

Theorem: For every function $f: \{0,1\}^* \rightarrow \{0,1\}$, Upper Bounds on the data complexity of *C*-Test For f*are equivalent to* Lower Bounds on the *C* circuit complexity of *f*

These "duals" provide an "alternate universe" where inputs become the "computational model" and circuits become the "inputs"

For example, the following are equivalent:
1) NP ⊄ P/poly (resp. NP ⊄ i.o. P/poly)
2) For every ε > 0 and for infinitely many s (resp. for every s), the data complexity of testing size-s circuits for SAT is at most O(2^{s^ε})

OPEN: Can we use data complexity to recover new proofs of old circuit lower bounds?

Let $f: \{0,1\}^* \to \{0,1\}$, and let $S(n) \ge 2n$ for all n. "Data Complexity of Testing Size-s Circuits for f" = Min number of inputs needed to distinguish: - circuits of size s computing a slice of f - circuits of size s that don't. Thm: If $f \in SIZE(S(n))$, then the data complexity of testing size-s circuits for f is $2^{\Omega(s^{-1}(s))}$, a.e. Thm: If $f \notin SIZE(2n \cdot S(n))$, then the data complexity of testing size-s circuits for f is at most $O\left(2^{S^{-1}(s)} + S^{-1}(s) \cdot s^2 \log s\right)$ i.o.

Ideas Behind The Proofs

Thm: If $f \in SIZE(S(n))$, then the data complexity of testing size-*s* circuits for *f* is $2^{\Omega(S^{-1}(s))}$, a.e.

- $f \in SIZE(S(n))$ implies that for every *n*-bit input *x*, there is a circuit of size S(n) + n which disagrees with *f* only at *x*.
- It follows that every test set for *f* on circuits of size S(n) + n has cardinality at least 2ⁿ.

Thm: If $f \notin SIZE(2n \cdot S(n))$, then the data complexity of testing size-*s* circuits for *f* is at most $O(2^{S^{-1}(s)} + S^{-1}(s) \cdot s^2 \log s)$ i.o.

Use "small counterexample" sets: can get an O(S(n) log S(n)) size test set for all circuits of size S(n) with n inputs.

For size-s circuits where n is "too large" to compute f, we have small test sets. For size-s circuits with n "small enough", it becomes possible to compute f within size s.

General Questions To Think More About

How can algorithms help prove lower bounds? How can properties of circuits be turned into algorithms for analyzing them?

How can lower bounds help design algorithms?

- We can make progress on both algorithms and lower bounds by studying them as a *unit*
- Next, an explicit example of algorithms proving lower bounds: NEXP vs ACC

Definition: ACC Circuits

An **ACC** circuit family { C_n } has the properties:

- Every C_n takes n bits of input and outputs a bit
- There is a fixed *d* such that every C_n has depth at most *d*
- There is a fixed *m* such that the gates of C_n are AND, OR, NOT, MODm (unbounded fan-in) MODm($x_1,...,x_t$) = 1 iff $\sum_i x_i$ is divisible by m

Remarks

- 1. The default size of C_n is polynomial in n
- 2. **Strength:** this is a **non-uniform** model of computation (can compute some undecidable languages)
- 3. *Weakness:* ACC circuits can be efficiently simulated by *constant-layer neural networks*